SPECIFICATIONS

Customer	天河星
Product Name	Multi-layer Chip Ferrite Bead
Sunlord Part Number	GZ3216D101TF
Customer Part Number	

[⊠New Released, □Revised]

SPEC No.: GZ10190032

[This SPEC is total 10 pages including specifications and appendix.] [ROHS Compliant Parts]



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For Customer approv Qualification Status:		Date:	ed
Approved By	Verified By	Re-checked By	Checked By
omments:			

[Version change history]

Rev.	Effective Date	Changed Contents	Change Reasons	Approved By
01	Mar.04,2019	New release	/	Hai Guo

Sunlord

Caution

All products listed in this specification are developed, designed and intended for use in general electronics equipment. The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require especially high reliability, or whose failure, malfunction or trouble might directly cause damage to society, person, or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below. Please contact us for more details if you intend to use our products in the following applications.

- 1. Aircraft equipment
- 2. Aerospace equipment
- 3. Undersea equipment
- 4. nuclear control equipment
- 5. military equipment
- 6. Power plant equipment
- 7. Medical equipment
- 8. Transportation equipment (automobiles, trains, ships, etc.)
- 9. Traffic signal equipment
- 10. Disaster prevention / crime prevention equipment
- 11. Data-processing equipment
- 12. Applications of similar complexity or with reliability requirements comparable to the applications listed in the above

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3216 [1206]

1. Scope

2)

This specification applies to GZ3216D101TF of multi-layer ferrite chip bead.

2. Product Description and Identification (Part Number)

- 1) Description:
 - GZ3216D101TF of multi-layer ferrite chip bead.
 - Broduct Identification (Part Number)

 GZ
 3216
 D
 101
 T

 ①
 ②
 ③
 ④
 ⑤



3	Material Code	
	D	

5	Packing		
Т	Tape Carrier Package		

6	HSF Products	
Hazardous Substance Free Products		

4	Nominal		Impedance
	Example		Nominal Value
	101		100Ω

External Dimensions (L X W)[mm]

3.2 X 1.6

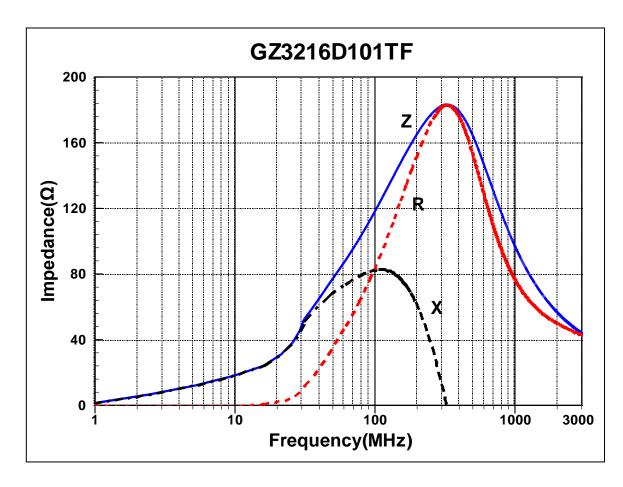
3. Electrical Characteristics

Part Number	Impedance (Ω)	Z Test Freq. (MHz)	DCR (Ω) Max.	Ir (mA) Max.
GZ3216D101TF	100±25%	100	0.10	1000

F

6

Impedance Frequency Characteristics

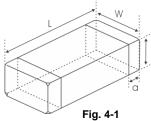


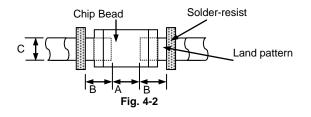
1) Operating and storage temperature range (individual chip without packing): -55℃ ~ +125℃.

2) Storage temperature range (packaging conditions):-10 $^\circ\!C$ ~+40 $^\circ\!C$ and RH 70% (Max.)

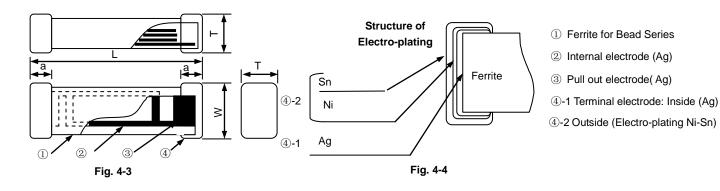
4. Shape and Dimensions

- 1) Dimensions and recommended PCB pattern for reflow soldering: See Fig.4-1, Fig.4-2 and Table 4-1.
- 2) Structure: See Fig. 4-3 and Fig. 4-4.





		[Table 4-1]			Unit: mm [i	nch]	
Туре	L	W	Т	а	А	В	С
3216 [1206]	3.2±0.2 [0.126±0.008]	1.6±0.2 [0.063±0.008]	0.85±0.2 [0.033±0.008]	0.5±0.3 [0.020±0.012]	1.80~2.50	1.00~1.50	1.20~2.00



3) Material Information: See Table 4-2.

[Table 4-2]				
Code	Part Name	Material Name		
1	Ferrite Body Ferrite Powder			
2	Inner Coils	Silver Paste		
3	Pull-out Electrode (Ag)	Silver Paste		
④-1	Terminal Electrode: Inside Ag	Termination Silver Composition		
④-2	Electro-Plating: Ni/Sn plating	Plating Chemicals		

5. Test and Measurement Procedures

5.1 Test Conditions

- 5.1.1 Unless otherwise specified, the standard atmospheric conditions for measurement/test as:
 - a. Ambient Temperature: 20±15℃
 - b. Relative Humidity: 65±20%
 - c. Air Pressure: 86kPa to 106kPa
- 5.1.2 If any doubt on the results, measurements/tests should be made within the following limits:
 - a. Ambient Temperature: 20±2°C
 - b. Relative Humidity: 65±5%
 - c. Air Pressure: 86kPa to 106kPa

5.2 Visual Examination

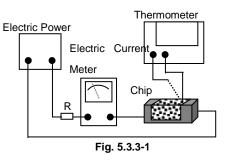
a. Inspection Equipment: 20x magnifier

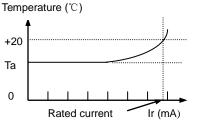
5.3 Electrical Test

- 5.3.1 DC Resistance (DCR)
 - a. Refer to Item 3.
 - b. Test equipment (Analyzer): High Accuracy Milliohmmeter-HP4338B or equivalent.
- 5.3.2 Impedance (Z)
 - a. Refer to Item 3.
 - Test equipment: High Accuracy RF Impedance /Material Analyzer-E4991A or equivalent. Test fixture: HP16197A for 0603, HP16192A for 1005/1608/2012/3216. Test signal: -20dBm or 50mV
 - c. Test frequency refers to Item 3.

5.3.3 Rated Current

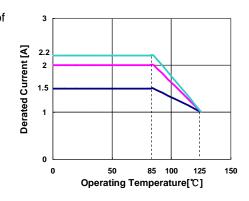
- a. Refer to Item 3.
- b. Test equipment (see Fig.5.3.3-1): Electric Power, Electric current meter, Thermometer.
- c. Measurement method (see Fig. 5.3.3-1):
 - 1. Set test current to be 0 mA.
 - 2. Measure initial temperature of chip surface.
 - 3. Gradually increase voltage and measure chip temperature for corresponding current.
- d. Definition of Rated Current (Ir): Ir is direct electric current as chip surface temperature rose just 20°C against chip initial surface temperature (Ta) (see Fig. 5.3.3-2)







e. When operating temperatures exceeding +85°C, derating of current is necessary for chip ferrite beads for which rated current is 1000mA over. Please apply the derating curve shown in chart according to the operating temperature.



5.4 Reliability Test

Items	Requirements	Test Methods and Remarks
5.4.1 Terminal Strength	No removal or split of the termination or other defects shall occur. Chip Chip Glass Epoxy Board Fig.5.4.1-1	 Solder the bead to the testing jig (glass epoxy board shown in Fig. 5.4.1-1) using leadfree solder. Then apply a force in the direction of the arrow. 10N force for 3216 series. Keep time: 10±1s. Speed: 1.0mm/s.
5.4.2 Resistance to Flexure	No visible mechanical damage. $ \begin{array}{c c c c c c c c c c c c c c c c c c c $	 Solder the bead to the test jig (glass epoxy board shown in Fig. 5.4.2-1) Using a leadfree solder. Then apply a force in the direction shown Fig. 5.4.2-2. Flexure: 2mm. Pressurizing Speed: 0.5mm/sec. Keep time: 30 sec.
5.4.3 Vibration	 No visible mechanical damage. Impedance change: within ±20% Cu pad Solder mask Glass Epoxy Board Fig. 5.4.3-1 	 Solder the bead to the testing jig (glass epoxy board shown in Fig. 5.4.3-1) using leadfree solder. The bead shall be subjected to a simple harmonic motion having total amplitude of 1.5 mm, the frequency being varied uniformly between the approximate limits of 10 and 55 Hz. The frequency range from 10 to 55 Hz and return to 10 Hz shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions (total of 6 hours).
5.4.4 Dropping	 No visible mechanical damage. Impedance change: within ±20%. 	Drop chip bead 10 times on a concrete floor from a height of 100 cm.
5.4.5 Temperature	Impedance change should be within $\pm 20\%$ of initial value measuring at 20% .	Temperature range: -55℃ ~ 125℃. Reference temperature: +20℃.
5.4.6 Solderability	 No visible mechanical damage. Wetting shall exceed 75% coverage for 0603 series; exceed 95% for others 	 Solder temperture:240±2℃ Duration: 3 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight.
5.4.7 Resistance to Soldering Heat	 No visible mechanical damage. Wetting shall exceed 75% coverage for 0603 series; exceed 95% for others Impedance change: within ±20%. 	 Solder temperature :260±3°C Duration: 5 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight. The chip shall be stabilized at normal condition for 1~2 hours before measuring.

Specifications for Multi-layer Chip Ferrite Bead

5.4.8	1 No mechanical damage.	① Temperature, Time: (See Fig.5.4.8-1)
Thermal Shock	2 Impedance change: Within ±20%.	-55°C for 30±3 min→125°C for 30±3min.
		② Transforming interval: Max. 20 sec.
	30 min. 30 min.	③ Tested cycle: 100 cycles.
	125°C	④ The chip shall be stabilized at normal condition for 1~2 hours
	Ambient	before measuring.
	Temperature	
	Fig. 5.4.8-1 20sec. (max.)	
5.4.9	① No mechanical damage.	① Temperature: -55±2°C
Resistance to	② Impedance change: within ±20%.	② Duration: 1000 ⁺²⁴ hours.
Low		③ The chip shall be stabilized at normal condition for 1~2 hours
Temperature		before measuring.
5.4.10	① No mechanical damage.	① Temperature: 125±2℃
Resistance to	② Impedance change: within ±20%.	② Duration: 1000 ⁺²⁴ hours.
High		③ The chip shall be stabilized at normal condition for 1~2 hours
Temperature		before measuring.
5.4.11	① No mechanical damage.	① Temperature: 60±2°C
Damp Heat	② Impedance change: Within ±20%.	② Humidity: 90% to 95% RH.
(Steady States)		③ Duration: 1000 ⁺²⁴ hours.
		④ The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.
5.4.12	① No visible mechanical damage.	① Temperature: 60±2℃
Loading Under	② Impedance change: within ±20%.	② Humidity: 90% to 95% RH.
Damp Heat		3 Duration: 1000 ⁺²⁴ hours.
		Applied current: Rated current.
		5 The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.
5.4.13	① No visible mechanical damage.	① Temperature: 125±2℃
Loading at High	2 Impedance change: within ±20%.	⁽²⁾ Duration: 1000^{+24} hours.
Temperature		③ Applied current: Rated current.
(Life Test)		④ The chip shall be stabilized at normal condition for 1~2 hours
		before measuring.

6. Packaging, Storage

6.1 Packaging

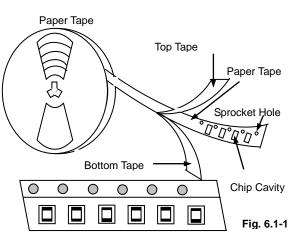
Tape Carrier Packaging:

Packaging code: T

- a. Tape carrier packaging are specified in attached figure Fig.6.1-1~3
- b. Tape carrier packaging quantity please see the following table:

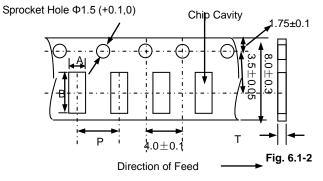
Туре	3216[1206]	
T(mm)	0.85±0.2	
Таре	Paper Tape	
Quantity	ЗК	

(1) Taping Drawings (Unit: mm)



Remark: The sprocket holes are to the right as the tape is pulled toward the user.

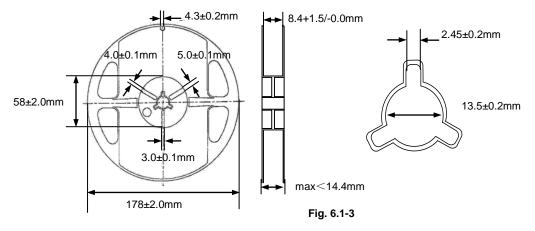
(2) Taping Dimensions (Unit: mm)



Paper Tape

	Туре	А	В	Р	T max
32	16[1206]	1.9±0.2	3.5±0.2	4.0±0.1	1.1

(3) Reel Dimensions (Unit: mm)



6.2 Storage

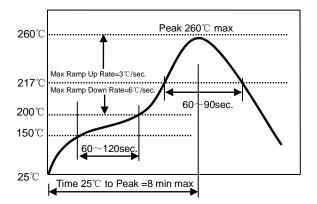
- a. The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to high humidity. Package must be stored at 40°C or less and 70% RH or less.
- b. The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to dust of harmful gas (e.g. HCl, sulfurous gas of H₂S).
- c. Packaging material may be deformed if package are stored where they are exposed to heat of direct sunlight.
- d. Solderability of the product s with external dimensions as 0603[0201] specified in Clause 5.4.6 shall be guaranteed for 6months from the date of delivery on condition that they are stored at the environment specified in Clause 3. For those parts, which passed more than 6 months shall be checked solder-ability before use.
- e. Solderability of the products, except ones with external dimensions as 0603[0201], specified in Clause 5.4.6 shall be guaranteed for 12 months from the date of delivery on condition that they are stored at the environment specified in Clause 3. For those parts, which passed more than 12 months shall be checked solder-ability before use.

7. Recommended Soldering Technologies

7.1 Re-flowing Profile:

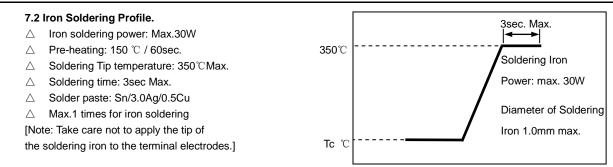
- \triangle Preheat condition: 150 ~200 °C/60~120sec.
- \triangle Allowed time above 217°C: 60~90sec.
- △ Max temp: 260°C
- \triangle Max time at max temp: 10sec.
- \triangle Solder paste: Sn/3.0Ag/0.5Cu
- \triangle Allowed Reflow time: 2x max

[Note: The reflow profile in the above table is only for qualification and is not meant to specify board assembly profiles. Actual board assembly profiles must be based on the customer's specific board design, solder paste and process, and should not exceed the parameters as the Reflow profile shows.]



Sunlord

Specifications for Multi-layer Chip Ferrite Bead



8. Supplier Information

- a) Supplier:
- Shenzhen Sunlord Electronics Co., Ltd.b) Manufacture:

Shenzhen Sunlord Electronics Co., Ltd.

c) Manufacturing Address:

Sunlord Industrial Park, Dafuyuan Industrial Zone, Guanlan, Shenzhen, China 518110